

Search Notes

Application/Control No.

10/657,698

Examiner

Michael Chu

Applicant(s)/Patent under
Reexamination

CHO ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	67.16	6/22/2006	MC
455	67.11	6/22/2006	MC
455	130	6/22/2006	MC
455	456.1	6/22/2006	MC
455	136	6/22/2006	MC
370	349	6/22/2006	MC
455	12.1	6/22/2006	MC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Subclass search within class 455, particularly subclasses 67.11 & 67.16 dealing with measuring system/part or phase.	6/22/2006	MC
Text search strategy on EAST.	6/22/2006	MC